Search Notes			

Application/Control No.	Applicant(s)/Paten Reexamination	Applicant(s)/Patent under Reexamination	
	SIREAU, JEAN-YVES		
Examiner	Art Unit		
JAGDISH PATEL	3624		

SEARCHED				
Class	Subclass	Date	Examiner	
705	37 3 <i>7</i>	3/30/2006 2(12/07 2/12/07	gnd gwl	
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
EAST (Patent Databases, US & Foreign)	3/30/2006 0 10 2016	gul	
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